



Probes for Applications

D3100-D5000-DV
MM-MMV-picoForce
Innova-CPII
Bioll
Escape
BioSZ
Caliber

		Market Group	Model Number	Conductive AFM (C-AFM)	Contact Mode Imaging	Electrostatic Force Microscopy (EFM)	Force Modulation Microscopy (FMM)	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Phase Imaging	Scanning Capacitance Microscopy (SCM)	Scanning Spreading Resistance Microscopy (SSRM)	Tapping Mode (in air)	Tapping Mode (in liquid)	Torsion Resonance Mode (TR mode)	Tunneling AFM (TUNA)
High Aspect Ratio	FIB1-100												x			
High Aspect Ratio	FIB2-100S												x			
High Aspect Ratio	FIB4-200												x			
High Aspect Ratio	FIB6-400												x			
High Aspect Ratio	FIB8-600												x			
High Aspect Ratio	HAR1-200												x			
High Aspect Ratio	IBMSC												x			
High Aspect Ratio	TESPA-HAR												x			
High Aspect Ratio	TESP-HAR												x			
High Resolution	DLCS												x			
High Resolution	TESP-SS												x			
Electrical	DDESP	x						x	x							x
Electrical	DDESP-FM	x	x					x	x	x						x
Electrical	MPP-11150-10	x								x						x
Electrical	MPP-21150-10	x	x					x	x	x						x
Electrical	OSCM-PT	x	x					x	x	x						x
Electrical	SCM-PIC	x						x	x							x
Electrical	SCM-PIT	x	x					x	x	x						x
Hardened	BESP												x			
Hardened	TESPD												x			
Indentation	PDNISP															
Indentation	DNISP															
Magnetic	MESP	x	x			x		x	x	x				x	x	
Magnetic	MESPSP					x										
Magnetic	MESP-HM					x										
Magnetic	MESP-HR					x										
Magnetic	MESP-LC					x										
Magnetic	MESP-LM					x										
Magnetic	MESP-RC					x										
Magnetic	MSNC-MFNM					x										
Silicon	ESP	x	x	x												
Silicon	FESP							x					x			x
Silicon	LTESP					x		x					x			x
Silicon	MPP-11100-10					x		x					x			
Silicon	MPP-11120-10					x		x					x			
Silicon	MPP-11200-10					x		x					x			
Silicon	MPP-11220-10					x		x					x			
Silicon	MPP-12100-10					x		x					x			
Silicon	MPP-12120-10					x		x					x			
Silicon	MPP-12200-10					x		x					x			
Silicon	MPP-12220-10					x		x					x			
Silicon	MPP-13100-10							x					x			
Silicon	MPP-13120-10							x					x			
Silicon	MPP-13200-10							x					x			
Silicon	MPP-13220-10							x					x			
Silicon	MPP-21100-10					x		x					x			
Silicon	MPP-21120-10					x		x					x			
Silicon	MPP-21200-10					x		x					x			
Silicon	MPP-21220-10					x		x					x			
Silicon	MPP-22100-10	x	x	x												
Silicon	MPP-22200-10	x	x	x												
Silicon	MPP-22220-10	x	x	x												
Silicon	MPP-23100-10					x							x			
Silicon	MPP-23120-10					x							x			
Silicon	MPP-23200-10					x							x			
Silicon	MPP-23220-10					x							x			
Silicon	MPP-31100-10	x	x	x												
Silicon	MPP-31120-10	x	x	x												
Silicon	MPP-31200-10	x	x	x												
Silicon	MPP-31220-10	x	x	x												
Silicon	MPP-32100-10	x	x	x												
Silicon	MPP-32120-10	x	x	x												
Silicon	MPP-32200-10	x	x	x												
Silicon	MPP-33100-10					x							x			
Silicon	MPP-33120-10					x							x			
Silicon	MPP-33200-10					x							x			
Silicon	MPP-33220-10					x							x			
Silicon	OLTESPA					x							x			
Silicon	OTESPA					x							x			
Silicon	RFESP					x							x			
Silicon	RTESP					x							x			
Silicon	RTESPA					x							x			
Silicon	TESP					x							x			
Silicon	TESPA					x							x			
Silicon Nitride	DNP	x	x	x												x
Silicon Nitride	DNP-S	x														x
Silicon Nitride	MLCT-AUNM	x	x	x												x
Silicon Nitride	MSCT-AUNM	x														x
Silicon Nitride	NP-20-UC	x	x	x												
Silicon Nitride	NPG-20															x
Silicon Nitride	OBL-35															x
Silicon Nitride	ORC8-35	x	x	x												
Silicon Nitride	OTR4-35	x	x	x												
Silicon Nitride	OTR8-105	x	x	x												
Silicon Nitride	OTR8-35	x	x	x												
Silicon Nitride	OTR8-W	x	x	x												
STM	DPT									x						
STM	DTT									x						

Notes:
 1. 'x' indicates applicable
 2. An AFM probe in air is either a contact mode probe or a tapping mode probe, regardless the specific application.
 3. Part number in red should be updated! Details provided in the comments.
 4. General purpose contact mode probes are the cantilevers with spring constant less than 1N/m. It was assumed that all contact mode cantilevers are OK for LFM measurements although sensitivity can be different.

Market Group		Model Number														
		Conductive AFM Option (C-AFM)	General Contact Mode Imaging	Electrostatic Force Imaging (EFM)	Force Modulation Microscopy (FMM)	Force - distance Measurement	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Phase Imaging	Scanning Capacitance Microscopy (SCM)	Scanning Spreading Resistance Microscopy (SSRM)	Surface Potential	General Tapping Mode Imaging (in air)	Tapping Mode Imaging (in liquid)	Torsion Resonance Mode (TRmode)	Tunneling AFM (TUNA)
Silicon	MPP-33200-10		x		x			x					x			
Silicon	MPP-33220-10		x		x			x					x			
Silicon	OLTESPA		x	x	x			x					x			
Silicon	OTESPA		x		x			x					x			
Silicon	RFESP		x	x	x			x					x			
Silicon	RTESP		x		x			x					x			
Silicon	RTESPA		x		x			x					x			
Silicon	TESP		x		x			x					x			
Silicon	TESPA		x		x			x					x			
Silicon Nitride	MLCT-AUNM	x	x	x	x	x							x			
Silicon Nitride	MSCT-AUNM	x					x							x		
Silicon Nitride	NP	x	x	x	x	x								x		
Silicon Nitride	NP-20-UC	x	x	x	x	x										
Silicon Nitride	NP-S	x					x							x		
Silicon Nitride	NPG-20	x		x										x		
Silicon Nitride	OBL-35	x		x										x		
Silicon Nitride	ORC8-35	x	x	x	x	x										
Silicon Nitride	OTR4-35	x	x	x	x	x										
Silicon Nitride	OTR8-105	x	x	x	x	x										
Silicon Nitride	OTR8-35	x	x	x	x	x										
Silicon Nitride	OTR8-W	x	x	x	x	x										
STM	PT									x						
STM	TT									x						

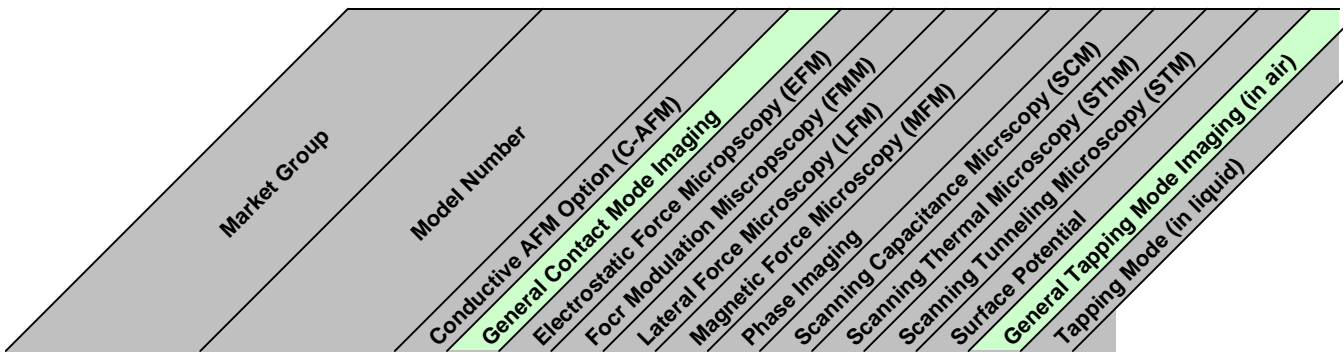
Notes:

1. 'x' indicates applicable
2. Part number in red needs to be updated, open for discussion.
3. Probe selection for force volume application depends on sample, similar to force modulation, including TESP/FESP/ESP groups.
4. Probe option for force-distance curve also depends on sample. Included in this matrix are the 3N/m and the contact mode tips.

Market Group		Model Number		Conductive AFM Option (C-AFM)	General Contact Mode Imaging	Electrostatic Force Imaging	Force Modulation Microscopy (FMM)	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Phase Imaging	Scanning Capacitance Microscopy (SCM)	Scanning Thermal Microscopy (SThM)	Surface Potential	General Tapping Mode Imaging (in air)	Tapping Mode (in liquid)
Silicon	MPP-21220-10			x					x					x	
Silicon	MPP-22100-10	x		x	x										
Silicon	MPP-22200-10	x		x	x										
Silicon	MPP-22220-10	x		x	x										
Silicon	MPP-23100-10			x					x					x	
Silicon	MPP-23120-10			x					x					x	
Silicon	MPP-23200-10			x					x					x	
Silicon	MPP-23220-10			x					x					x	
Silicon	MPP-31100-10	x		x	x										
Silicon	MPP-31120-10	x		x	x										
Silicon	MPP-31123-10	x		x	x										
Silicon	MPP-31200-10	x		x	x										
Silicon	MPP-31220-10	x		x	x										
Silicon	MPP-32100-10	x		x	x										
Silicon	MPP-32120-10	x		x	x										
Silicon	MPP-32200-10	x		x	x										
Silicon	MPP-33100-10			x					x					x	
Silicon	MPP-33120-10			x					x					x	
Silicon	MPP-33200-10			x					x					x	
Silicon	MPP-33220-10			x					x					x	
Silicon	OLTESPA			x					x					x	
Silicon	OTESPA			x					x					x	
Silicon	RFESP			x					x					x	
Silicon	RTESP			x					x					x	
Silicon	RTESPA			x					x					x	
Silicon	TESP			x					x					x	
Silicon	TESPA			x					x					x	
Silicon Nitride	DNP	x		x	x										
Silicon Nitride	DNP-S	x			x										
Silicon Nitride	MLCT-AUNM	x		x	x										x
Silicon Nitride	MLCT-AUMT-A	x		x	x										
Silicon Nitride	MLCT-AUMT-BF	x		x	x										
Silicon Nitride	MLCT-NOMT-A	x		x	x										
Silicon Nitride	MLCT-NOMT-BF	x		x	x										
Silicon Nitride	MSCT-AUNM	x			x										x
Silicon Nitride	MSCT-AUMT-A	x			x										
Silicon Nitride	MSCT-AUMT-BF	x			x										
Silicon Nitride	MSCT-NOMT-A	x			x										
Silicon Nitride	MSCT-NOMT-BF	x			x										
Silicon Nitride	NP	x		x	x										
Silicon Nitride	NP-20-UC	x		x	x										
Silicon Nitride	NP-S	x			x										
Silicon Nitride	NPG-20	x													
Silicon Nitride	OBL-35	x													
Silicon Nitride	ORC8-35	x		x	x										
Silicon Nitride	OTR4-35	x		x	x										
Silicon Nitride	OTR8-105	x		x	x										
Silicon Nitride	OTR8-35	x		x	x										
Silicon Nitride	OTR8-W	x		x	x										
Wollaston Wire	CLST-NOMB									x					
STM	CLST-PTBO										x				

Notes:

1. 'x' indicated applicable



2. Part number in red are suggested to be updated

		Market Group		Model Number		General Contact Mode Imaging	Force-distance Measurements	Phase Imaging	General Tapping Mode Imaging (in air)	Tapping Mode (in liquid)
High Aspect Ratio	FIB1-100					x				
High Aspect Ratio	FIB2-100S					x				
High Aspect Ratio	FIB4-200					x				
High Aspect Ratio	FIB6-400					x				
High Aspect Ratio	FIB8-600					x				
High Aspect Ratio	HAR1-200					x				
High Aspect Ratio	IBMSC					x				
High Aspect Ratio	TESPA-HAR					x				
High Aspect Ratio	TESP-HAR					x				
High Resolution	DLCS					x				
High Resolution	TESP-SS					x				
Silicon	ESP	x	x							
Silicon	FESP			x	x	x				
Silicon	LTESP				x	x				
Silicon	MPP-11100-10				x	x				
Silicon	MPP-11120-10				x	x				
Silicon	MPP-11200-10				x	x				
Silicon	MPP-11220-10				x	x				
Silicon	MPP-12100-10				x	x				
Silicon	MPP-12120-10				x	x				
Silicon	MPP-12200-10				x	x				
Silicon	MPP-12220-10				x	x				
Silicon	MPP-13100-10				x	x				
Silicon	MPP-13120-10				x	x				
Silicon	MPP-13200-10				x	x				
Silicon	MPP-13220-10				x	x				
Silicon	MPP-21100-10		x	x	x	x				
Silicon	MPP-21120-10		x	x	x	x				
Silicon	MPP-21200-10		x	x	x	x				
Silicon	MPP-21220-10		x	x	x	x				
Silicon	MPP-22100-10	x	x							
Silicon	MPP-22200-10	x	x							
Silicon	MPP-22220-10	x	x							
Silicon	MPP-23100-10				x	x				
Silicon	MPP-23120-10				x	x				
Silicon	MPP-23200-10				x	x				
Silicon	MPP-23220-10				x	x				
Silicon	MPP-31100-10	x	x							
Silicon	MPP-31120-10	x	x							
Silicon	MPP-31200-10	x	x							
Silicon	MPP-31220-10	x	x							

Market Group		Model Number		General Contact Mode Imaging	Force-distance Measurements	Phase Imaging	General Tapping Mode Imaging (in air)	Tapping Mode (in liquid)
Silicon	MPP-32100-10	x	x					
Silicon	MPP-32120-10	x	x					
Silicon	MPP-32200-10	x	x					
Silicon	MPP-33100-10				x	x		
Silicon	MPP-33120-10				x	x		
Silicon	MPP-33200-10				x	x		
Silicon	MPP-33220-10				x	x		
Silicon	OLTESPA				x	x		
Silicon	OTESPA				x	x		
Silicon	RFESP				x	x		
Silicon	RTESP				x	x		
Silicon	RTESPA				x	x		
Silicon	TESP				x	x		
Silicon	TESPA				x	x		
Silicon Nitride	DNP	x	x					x
Silicon Nitride	DNP-S	x	x					x
Silicon Nitride	MLCT-AUNM	x	x					x
Silicon Nitride	MSCT-AUNM	x	x					x
Silicon Nitride	NP-20-UC	x	x					
Silicon Nitride	NPG-20	x	x					x
Silicon Nitride	OBL-35	x	x					x
Silicon Nitride	ORC8-35	x	x					
Silicon Nitride	OTR4-35	x	x					
Silicon Nitride	OTR8-105	x	x					
Silicon Nitride	OTR8-35	x	x					
Silicon Nitride	OTR8-W	x	x					

Notes:

1. 'x' without comments indicates possible usage on all SPM platforms except Explorer
2. For force-distance application, it was assumed that contact mode tips and <2N/m probes are applicable.

Market Group	Model Number	General Contact Mode Imaging	Electrostatic Force Microscopy (EFM)	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Phase Imaging	Scanning Surface Potential	General Tapping Mode Imaging (in air)	Tapping Mode (in liquid)	Torsion Resonance Mode (TR mode)
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High Aspect Ratio	FIB1-100							x		
High Aspect Ratio	FIB2-100S							x		
High Aspect Ratio	FIB4-200							x		
High Aspect Ratio	FIB6-400							x		
High Aspect Ratio	FIB8-600							x		
High Aspect Ratio	HAR1-200							x		
High Aspect Ratio	IBMSC							x		
High Aspect Ratio	TESPA-HAR							x		
High Aspect Ratio	TESP-HAR							x		
High Resolution	DLCS							x		
High Resolution	TESP-SS							x		
Electrical	DDESP									
Electrical	DDESP-FM	x				x				
Electrical	MPP-11150-10									
Electrical	MPP-21150-10	x				x				
Electrical	OSCM-PT	x				x				
Electrical	SCM-PIC									
Electrical	SCM-PIT	x				x				
Hardened	BESP									
Hardened	TESPD							x		
Indentation	PDNISP									
Indentation	DNISP									
Magnetic	MESP	x		x		x				x
Magnetic	MESPSP			x						
Magnetic	MESP-HM			x						
Magnetic	MESP-HR			x						
Magnetic	MESP-LC			x						
Magnetic	MESP-LM			x						
Magnetic	MESP-RC			x						
Magnetic	MSNC-MFNM			x						
Silicon	ESP	x		x						
Silicon	FESP					x		x		x
Silicon	LTESP					x		x		x
Silicon	MPP-11100-10					x		x		
Silicon	MPP-11120-10					x		x		
Silicon	MPP-11200-10					x		x		
Silicon	MPP-11220-10					x		x		
Silicon	MPP-12100-10					x		x		
Silicon	MPP-12120-10					x		x		
Silicon	MPP-12200-10					x		x		
Silicon	MPP-12220-10					x		x		
Silicon	MPP-13100-10					x		x		
Silicon	MPP-13120-10					x		x		
Silicon	MPP-13200-10					x		x		
Silicon	MPP-13220-10					x		x		
Silicon	MPP-21100-10					x		x		
Silicon	MPP-21120-10					x		x		
Silicon	MPP-21200-10					x		x		
Silicon	MPP-21220-10					x		x		
Silicon	MPP-22100-10	x		x						
Silicon	MPP-22200-10	x		x						
Silicon	MPP-22220-10	x		x						
Silicon	MPP-23100-10					x		x		
Silicon	MPP-23120-10					x		x		
Silicon	MPP-23200-10					x		x		
Silicon	MPP-23220-10					x		x		
Silicon	MPP-31100-10	x		x						
Silicon	MPP-31120-10	x		x						
Silicon	MPP-31200-10	x		x						
Silicon	MPP-31220-10	x		x						
Silicon	MPP-32100-10	x		x						
Silicon	MPP-32120-10	x		x						
Silicon	MPP-32200-10	x		x						
Silicon	MPP-33100-10					x		x		
Silicon	MPP-33120-10					x		x		
Silicon	MPP-33200-10					x		x		
Silicon	MPP-33220-10					x		x		
Silicon	OLTESPA					x		x		
Silicon	OTESPA					x		x		
Silicon	RFESP					x		x		
Silicon	RTESP					x		x		
Silicon	RTESPA					x		x		
Silicon	TESP					x		x		
Silicon	TESPA					x		x		
Silicon Nitride	DNP	x		x						x
Silicon Nitride	DNP-S	x		x						x
Silicon Nitride	MLCT-AUNM	x		x						x
Silicon Nitride	MSCT-AUNM	x		x						x
Silicon Nitride	NP-20-UC	x		x						
Silicon Nitride	NPG-20	x								x
Silicon Nitride	OBL-35	x								x
Silicon Nitride	ORC8-35	x		x						
Silicon Nitride	OTR4-35	x		x						
Silicon Nitride	OTR8-105	x		x						
Silicon Nitride	OTR8-35	x		x						
Silicon Nitride	OTR8-W	x		x						
STM	DPT									
STM	DTT									

- Notes:
1. 'x' indicates applicable
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 3. Part number in red should be updated! Details provided in the comments.
 4. General purpose contact mode probes are the cantilevers with spring constant less than 1N/m. It was assumed that all contact mode cantilevers are OK for LFM measurements although sensitivity can be different.

100907-probe matrix-BioSZ		*	*	*	*	*	*	*	*	*	*	*	*	*	*
Market Group	Model Number	General Contact Mode Imaging	Electrostatic Force Microscopy (EFM)	Force Modulation Microscopy (FMM)	Force-Distance Microscopy (FDM)	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Nano-indentation and Scratching	Phase imaging	Scanning Tunneling Microscopy (STM)	Tapping Mode	Tapping Mode (in liquid)			
High Aspect Ratio	FIB1-100														x
High Aspect Ratio	FIB2-100S														x
High Aspect Ratio	FIB4-200														x
High Aspect Ratio	FIB6-400														x
High Aspect Ratio	FIB8-600														x
High Aspect Ratio	HAR1-200														x
High Aspect Ratio	IBMSC														x
High Aspect Ratio	TESPA-HAR														x
High Aspect Ratio	TESP-HAR														x
High Resolution	DLCS														x
High Resolution	TESP-SS														x
Electrical	MPP-11150-10		x												
Electrical	MPP-21150-10		x												
Electrical	OSCM-PT		x												
Electrical	SCM-PIC														
Electrical	SCM-PIT		x												
Hardened	BESP														
Hardened	TESPD						x								x
Indentation	PDNISP						x								
Indentation	DNISP						x								
Magnetic	MESP		x				x								
Magnetic	MESPSP						x								
Magnetic	MESP-HM						x								
Magnetic	MESP-HR						x								
Magnetic	MESP-LC						x								
Magnetic	MESP-LM						x								
Magnetic	MSNC-MFNM						x								
Silicon	ESP	x		x	x	x									
Silicon	FESP			x	x			x							x
Silicon	LTESP			x				x	x						x
Silicon	MPP-11100-10			x				x	x						x
Silicon	MPP-11120-10			x				x	x						x
Silicon	MPP-11200-10			x				x	x						x
Silicon	MPP-11220-10			x				x	x						x
Silicon	MPP-12100-10			x	x				x						x
Silicon	MPP-12120-10			x	x				x						x
Silicon	MPP-12200-10			x	x				x						x
Silicon	MPP-12220-10			x	x				x						x
Silicon	MPP-13100-10								x	x					x
Silicon	MPP-13120-10								x	x					x
Silicon	MPP-13200-10								x	x					x
Silicon	MPP-13220-10								x	x					x
Silicon	MPP-21100-10			x	x					x					x
Silicon	MPP-21120-10			x	x					x					x
Silicon	MPP-21200-10			x	x					x					x

Market Group	Model Number	General Contact Mode Imaging	Electrostatic Force Microscopy (EFM)	Force Modulation Microscopy (FMM)	Lateral Force Microscopy (LFM)	Magnetic Force Microscopy (MFM)	Nano-indentation and Scratching	Phase imaging	Scanning Tunneling Microscopy (STM)	Tapping Mode (in liquid)
Silicon	MPP-21220-10		x	x				x	x	
Silicon	MPP-22100-10	x	x	x	x					
Silicon	MPP-22200-10	x	x	x	x					
Silicon	MPP-22220-10	x	x	x	x					
Silicon	MPP-23100-10		x				x	x		
Silicon	MPP-23120-10		x				x	x		
Silicon	MPP-23200-10		x				x	x		
Silicon	MPP-23220-10		x				x	x		
Silicon	MPP-31100-10	x	x	x	x					
Silicon	MPP-31120-10	x	x	x	x					
Silicon	MPP-31150-10	x	x	x	x					
Silicon	MPP-31200-10	x	x	x	x					
Silicon	MPP-31220-10	x	x	x	x					
Silicon	MPP-32100-10	x	x	x	x					
Silicon	MPP-32120-10	x	x	x	x					
Silicon	MPP-32200-10	x	x	x	x					
Silicon	MPP-33100-10		x				x	x		
Silicon	MPP-33120-10		x				x	x		
Silicon	MPP-33200-10		x				x	x		
Silicon	MPP-33220-10		x				x	x		
Silicon	OLTESPA		x	x			x	x		
Silicon	OTESPA		x			x	x	x		
Silicon	RFESP		x	x			x	x		
Silicon	RTESP		x			x	x	x		
Silicon	RTESPA		x			x	x	x		
Silicon	TESP		x			x	x	x		
Silicon	TESPA		x			x	x	x		
Silicon Nitride	DNP	x	x	x	x					x
Silicon Nitride	DNP-S	x		x	x					x
Silicon Nitride	MLCT-AUNM	x	x	x	x					x
Silicon Nitride	MSCT-AUNM	x		x	x					x
Silicon Nitride	NP-20-UC	x	x	x	x					
Silicon Nitride	NPG-20	x		x						x
Silicon Nitride	OBL-35	x		x						x
Silicon Nitride	ORC8-35	x	x	x	x					
Silicon Nitride	OTR4-35	x	x	x	x					
Silicon Nitride	OTR8-105	x	x	x	x					
Silicon Nitride	OTR8-35	x	x	x	x					
Silicon Nitride	OTR8-W	x	x	x	x					
STM	DPT							x		
STM	DTT							x		

Notes:

1. 'x' indicates applicable
2. Part number in red should be updated! Details provided in the comments.

100907-probe matrix-Caliber

		<div style="display: flex; justify-content: space-between;"> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Market Group</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Model Number</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">General Contact Mode Imaging</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Force Distance Spectroscopy</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Lateral Force Microscopy (LFM)</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Phase Imaging</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">General Tapping Mode Imaging (in air)</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Tapping Mode (in liquid)</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Electrostatic Force Microscopy (EFM)</div> <div style="writing-mode: vertical-rl; transform: rotate(180deg);">Magnetic Force Microscopy (MFM)</div> </div>							
Magnetic	1670-00							x	x
Electric	1600-00							x	
Silicon	1650-00				x	x			
Silicon	FESP-CLBR		x		x	x			
Silicon	1660-00				x	x			
Silicon	1950-00	x	x	x					
Silicon Nitride	MLCT-EXMT-A	x	x	x			x		
Silicon Nitride	MLCT-EXMT-BF	x	x	x			x		
Silicon Nitride	MSCT-EXMT-A	x	x	x			x		
Silicon Nitride	MSCT-EXMT-BF	x	x	x			x		

Notes:

- 'x' indicates applicable.
- Applications shaded in green are not listed on Veeco.com although the applications may be available on Caliber